

VIRTUAL SEMINAR Thursday, 11.03.2021 at 13:00

Scanning electron microscopy and electron probe microanalysis: SEM, EDS, WDS and EBSD

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An overview of scanning electron microscopy (SEM), energydispersive X-ray spectroscopy (EDS), wavelength-dispersive X-ray spectroscopy (WDS) and electron backscatter diffraction (EBSD) characterization methods will be presented. With SEM we achieve imaging at milimeter, micrometer and nanometer scale, with EDS and WDS we obtain qualitative and quantitative analysis of chemical composition and with EBSD we perform crystallographic orientation measurements and phase identification. SEM, EDS, WDS and EBSD are nowadays indispensable analytical methods which are widely used for general and versatile microstructural characterization of various materials.

Kindly invited.

